



Integrated Device Technology, Inc.

HIGH-SPEED CMOS OCTAL D REGISTER (3-STATE)

IDT54/74AHCT374

FEATURES:

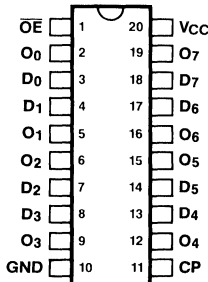
- Equivalent to ALS speeds and output drive over full temperature and voltage supply extremes
- 10ns typical address to output delay
- $I_{OL} = 14\text{mA}$ over full military temperature range
- CMOS power levels (5mW typ. static)
- Both CMOS and TTL output compatible
- Substantially lower input current levels than ALS (5μA max.)
- Octal D register (3-state)
- 100% product assurance screening to MIL-STD-883, Class B is available
- JEDEC standard pinout for DIP and LCC

DESCRIPTION:

The IDT54/74AHCT374 are 8-bit registers built using advanced CEMOS™, a dual metal CMOS technology. This register consists of eight D-type flip-flops with a buffered common clock and buffered three-state output control. When the output enable (\overline{OE}) input is LOW, the eight outputs are enabled. When the \overline{OE} input is HIGH, the outputs are in the three-state conditions.

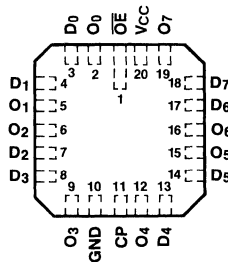
Input data meeting the set-up and hold time requirements of the D inputs is transferred to the O outputs on the LOW-to-HIGH transition of the clock input.

PIN CONFIGURATIONS



SSD54/74AHCT374-001

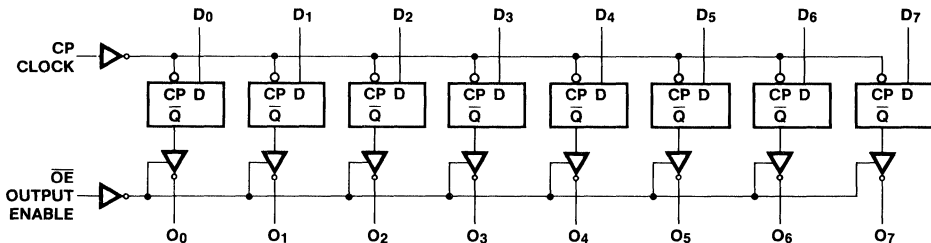
DIP
TOP VIEW



SSD54/74AHCT374-002

LCC
TOP VIEW

FUNCTIONAL BLOCK DIAGRAM



SSD54/74AHCT374-003

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MILITARY AND COMMERCIAL TEMPERATURE RANGES

JULY 1986

5

ABSOLUTE MAXIMUM RATING⁽¹⁾

SYMBOL	RATING	COMMERCIAL	MILITARY	UNIT
V _{TERM}	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
T _A	Operating Temperature	0 to +70	-55 to +125	°C
T _{BIAS}	Temperature Under Bias	-55 to +125	-65 to +135	°C
T _{STG}	Storage Temperature	-55 to +125	-65 to +155	°C
I _{OUT}	DC Output Current	120	120	mA

NOTE:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

T_A = 0°C to +70°C V_{CC} = 5.0V ± 5% Min. = 4.75V Max. = 5.25V (Commercial)
 T_A = -55°C to +125°C V_{CC} = 5.0V ± 10% Min. = 4.50V Max. = 5.50V (Military)
 V_{LC} = 0.2V
 V_{HC} = V_{CC} - 0.2V

SYMBOL	PARAMETER	TEST CONDITIONS ⁽¹⁾	MIN.	TYP. ⁽²⁾	MAX.	UNIT	
V _{IH}	Input HIGH Level	Guaranteed Logic High Level	2.0	—	—	V	
V _{IL}	Input LOW Level	Guaranteed Logic Low Level	—	—	0.8	V	
I _{IH}	Input HIGH Current	V _{CC} = Max., V _{IN} = V _{CC}	—	—	5	μA	
I _{IL}	Input LOW Current	V _{CC} = Max., V _{IN} = GND	—	—	-5	μA	
I _{SC}	Short Circuit Current	V _{CC} = Max. ⁽³⁾	-60	-120	—	mA	
V _{OH}	Output HIGH Voltage	V _{CC} = 3V, V _{IN} = V _{LC} or V _{HC} , I _{OH} = -32μA	V _{HC}	V _{CC}	—	V	
		V _{CC} = Min. V _{IN} = V _{IH} or V _{IL}	I _{OH} = -150μA	V _{HC}	V _{CC}		—
			I _{OH} = -1.0mA MIL.	2.4	4.3		—
			I _{OH} = -2.6mA COM'L.	2.4	4.3		—
V _{OL}	Output LOW Voltage	V _{CC} = 3V, V _{IN} = V _{LC} or V _{HC} , I _{OL} = 300μA	—	GND	V _{LC}	V	
		V _{CC} = Min. V _{IN} = V _{IH} or V _{IL}	I _{OL} = 300μA	—	GND		V _{LC}
			I _{OL} = 14mA MIL.	—	—		0.4
			I _{OL} = 24mA COM'L.	—	—		0.5

NOTES:

- For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V_{CC} = 5.0V, +25°C ambient and maximum loading.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.

POWER SUPPLY CHARACTERISTICS

$$V_{LC} = 0.2V; V_{HC} = V_{CC} - 0.2V$$

SYMBOL	PARAMETER	TEST CONDITIONS ⁽¹⁾		MIN.	TYP. ⁽²⁾	MAX.	UNIT
I_{CCQ}	Quiescent Power Supply Current	$V_{CC} = \text{Max.}$ $V_{IN} \geq V_{HC}; V_{IN} \leq V_{LC}$ $f_{CP} = f_i = 0$		—	0.001	1.5	mA
I_{CCT}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V$ ⁽³⁾		—	0.5	1.6	mA
I_{CCD}	Dynamic Power Supply Current	$V_{CC} = \text{Max.}$ Outputs Open OE = GND One Bit Toggling 50% Duty Cycle	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$	—	0.15	0.25	mA/ MHz
I_{CC}	Total Power Supply ⁽⁴⁾ Current	$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 1.0\text{MHz}$ 50% Duty Cycle OE = GND One Bit Toggling at $f_i = 500\text{kHz}$ 50% Duty Cycle	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ (AHCT)	—	0.15	1.8	mA
			$V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$	—	0.65	3.4	
		$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 1.0\text{MHz}$ 50% Duty Cycle OE = GND Eight Bits Toggling at $f_i = 250\text{kHz}$ 50% Duty Cycle	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ (AHCT)	—	0.63	2.2	
			$V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$	—	2.88	9.4	

NOTES:

1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient and maximum loading.

3. Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND.

$$4. I_{CC} = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$$

$$I_{CC} = I_{CCQ} + I_{CCT}D_HN_T + I_{CCD}(f_{CP}/2 + f_iN_i)$$

I_{CCQ} = Quiescent Current

I_{CCT} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)

D_H = Duty Cycle for TTL Inputs High

N_T = Number of TTL Inputs at D_H

I_{CCD} = Dynamic Current caused by an Input Transition pair (HLH or LHL)

f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)

f_i = Input Frequency





N_i = Number of Inputs at f_i


All currents are in milliamps and all frequencies are in megahertz.

DEFINITION OF FUNCTIONAL TERMS

PIN NAMES	DESCRIPTION
D _i	The D flip-flop data inputs.
CP	Clock Pulse for the register. Enters data on the LOW-to-HIGH transition.
O _i	The register three-state outputs.
OE	Output Control. An active-LOW three-state control used to enable the outputs. A HIGH level input forces the outputs to the high impedance (off) state.

TRUTH TABLE

FUNCTION	INPUTS			OUTPUTS	INTERNAL
	OE	CLOCK	D _i	O _i	Q _i
Hi-Z	H H	L H	X X	Z Z	NC NC
LOAD REGISTER	L L H H	   	L H L H	L H Z Z	L H L H

H = HIGH
 L = LOW
 X = Don't Care
 Z = High Impedance
 = LOW-to-HIGH transition
 NO = No Change

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

SYMBOL	PARAMETER	CONDITION	TYPICAL	COMMERCIAL		MILITARY		UNITS
				MIN.	MAX.	MIN.	MAX.	
t _{PLH} t _{PHL}	Propagation Delay CP to O _N	C _L = 50 pf R _L = 500 Ω	10.0	3.0	16.0	3.0	18.0	ns
t _{ZH} t _{ZL}	Output Enable Time		11.0	5.0	18.0	5.0	20.0	ns
t _{HZ} t _{LZ}	Output Disable Time		9.0	2.0	18.0	2.0	24.0	ns
t _S	Setup Time HIGH or LOW D _N to CP		2.0	10.0	—	10.0	—	ns
t _H	Hold Time HIGH or LOW D _N to CP		0.5	3.0	—	4.0	—	ns
t _W	CP Pulse Width HIGH or LOW		10.0	14.0	—	16.5	—	ns